

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	291	(375/226).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/22 19:34
S2	191	("5929683" "6359878" "6411244" "7136773" "20050129104" "20050149784" "20050267696" "20060178850" "20060184332" "20060291548" "5654657" "5710517" "5245636" "4771400" "6134670" "4330753" "4985900" "5239494" "5305362" "5452333" "5761254" "5808509" "5825834" "5835501" "5862411" "5961577" "5963104" "5974103" "5987620" "6005425" "6065126" "6128359" "6263034" "6546345" "6594595" "6701269" "6717789" "6737852" "6782404" "6898535" "6931335" "6937949" "6973147" "6985823" "7058535" "7062393" "7127018" "7158899" "7193481" "7203460" "7203610" "20020176525" "20030018442" "20030031284" "20030055854" "20030094937" "20030095304" "20030103302" "20030165208" "20030191592" "20040042578" "20040153267" "20040210790" "20040250179" "20050010707" "20050069031" "20050075810" "20050079822" "20050080574" "20050097420" "20050111536" "20050152488" "20050175355" "20050177758" "20050182588" "20050231294" "20050232345" "20050286627" "20060045175" "20060047450" "20060069967" "20060098768" "20060100801" "20060107126" "20060126714" "20060132340" "20060165205" "20060171485" "20060173943" "20060193418" "20060251200" "20070002964" "20070036256" "20070043797" "4310795" "4843309" "5267019" "5339334" "5394106" "5598130" ). pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 19:39

## EAST Search History

S3	92	S2 and @pd<"20031216"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:25
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## EAST Search History

S4	92	(US-20020176525-\$ or US-20030018442-\$ or US-20030031284-\$ or US-20030055854-\$ or US-20030095304-\$ or US-20030094937-\$ or US-20030103302-\$ or US-20030165208-\$ or US-20030191592-\$).did. or (US-4310795-\$ or US-4330753-\$ or US-4771400-\$ or US-4843309-\$ or US-4985900-\$ or US-5239494-\$ or US-5245636-\$ or US-5267019-\$ or US-5305362-\$ or US-5339334-\$ or US-5394106-\$ or US-5452333-\$ or US-5598130-\$ or US-5654657-\$ or US-5710517-\$ or US-5761254-\$ or US-5808509-\$ or US-5825834-\$ or US-5835501-\$ or US-5862411-\$ or US-5929683-\$ or US-5963104-\$ or US-5961577-\$ or US-5974103-\$ or US-5987620-\$ or US-6005425-\$). did. or (US-6065126-\$ or US-6128359-\$ or US-6134670-\$ or US-6263034-\$ or US-6359878-\$ or US-6411244-\$ or US-6546345-\$ or US-6594595-\$).did. or (DE-4310795-\$).did. or (NL-6703586-\$ or GB-1393787-\$ or CS-7203610-\$ or DE-2914072-\$ or US-4330753-\$ or EP-233679-\$ or US-4771400-\$ or EP-481847-\$ or EP-335496-\$ or US-5239494-\$ or US-5267019-\$ or EP-575058-\$ or DE-4310795-\$ or GB-2274561-\$ or US-5339334-\$ or US-5394106-\$ or EP-708522-\$ or DE-19629869-\$ or GB-2274221-\$ or CA-2179235-\$ or EP-817419-\$ or EP-828360-\$ or US-5761254-\$ or JP-10209821-\$ or US-5808509-\$ or US-5825834-\$). did. or (US-5862411-\$ or US-5963104-\$ or US-5987620-\$ or US-6005425-\$ or US-6065126-\$ or US-6128359-\$ or US-6134670-\$ or US-6263034-\$ or US-6266385-\$ or US-6411244-\$ or WO-200275334-\$ or WO-200282655-\$ or EP-1265391-\$ or CA-2351802-\$ or US-6546345-\$ or WO-2003036313-\$ or WO-2003042722-\$ or US-20030103302-\$ or US-20030165208-\$ or WO-2003073115-\$ or US-3693629-\$ or DE-2212866-\$).did.	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2007/05/22 22:11
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## EAST Search History

S5	2	S4 and (jitter near3 test\$3) and serial	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:21
S6	1	S5 and jitter and PRBS	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 19:43
S7	561	(jitter near2 generat\$3) and (low adj2 pass adj2 filter)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:25
S8	322	S7 and @pd<"20031216"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:41
S9	1	S8 and (jitter adj2 transfer adj2 function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:26
S10	8	S8 and (sinusoidal adj2 jitter)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:51
S11	2	S8 and (jitter adj2 ratio)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:40
S12	27	(sinusoidal adj2 jitter) and (deterministic adj2 jitter)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:55

## EAST Search History

S13	3	S12 and @pd<"20031216"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:51
S14	10	(sinusoidal adj2 jitter) and (plurality with sinusoid\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:51
S15	1	S14 and @pd<"20031216"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 21:56
S16	38	(sinusoidal adj2 jitter) and ((deterministic or square) adj4 jitter)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:01
S17	8	S16 and @pd<"20031216"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:01
S18	1	S17 and (jitter adj2 transfer adj2 function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:00
S19	6	(sinusoidal adj2 jitter) and ((deterministic or square) adj4 jitter) and (alignment adj3 jitter)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:01
S20	1	S19 and @pd<"20031216"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:02

## EAST Search History

S21	68	S4 and (jitter)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:11
S22	9	S21 and (sinusoidal adj2 jitter)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:11
S23	1	S22 and (deterministic adj jitter)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:11
S24	1	(US-5394106-\$).did.	USPAT	OR	ON	2007/05/22 22:14
S25	2	("5793822").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/22 22:14
S26	1	(US-5793822-\$).did.	USPAT	OR	ON	2007/05/22 22:15
S27	1	(US-20030202573-\$).did.	US-PGPUB	OR	ON	2007/05/22 22:15
S28	523	327/107	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:20
S29	11676	((327/107) or (375/371,226,232,344,235,376) or (714/704) or (398/5) or (360/51)).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/22 22:20
S30	50	S29 and (jitter near3 test\$3) and serial	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/22 22:21

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IEEE JNL IEEE Journal or Magazine

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IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

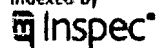
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IEEE JNL IEEE Journal or Magazine

IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

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## 1. Extraction of peak-to-peak and RMS sinusoidal jitter using an analytic sig

Yamaguchi, T.J.; Soma, M.; Ishida, M.; Watanabe, T.; Ohmi, T.;

[VLSI Test Symposium, 2000. Proceedings. 18th IEEE](#)

30 April-4 May 2000 Page(s):395 - 402

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## 2. Problems with jitter measurement in PDH/SDH-based digital telecommun

Angrisani, L.; Baccigalupi, A.; D'Angiolo, G.;

[Instrumentation and Measurement, IEEE Transactions on](#)

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## 3. A method for measuring the cycle-to-cycle period jitter of high-frequency

Yamaguchi, T.J.; Soma, M.; Halter, D.; Raina, R.; Nissen, J.; Ishida, M.;

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29 April-3 May 2001 Page(s):102 - 110

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## 4. A new method for testing jitter tolerance of SerDes devices using sinusoi

Yamaguchi, T.J.; Soma, M.; Ishida, M.; Musha, H.; Malarsie, L.;

[Test Conference, 2002. Proceedings. International](#)

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## 5. Extraction of instantaneous and RMS sinusoidal jitter using an analytic s

Yamaguchi, T.J.; Soma, M.; Ishida, M.; Watanabe, T.; Ohmi, T.;

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